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Kind regards,

Team Nexperia



PMZ250UN N-channel TrenchMOS extremely low level FET Rev. 01 – 21 February 2008 P

Product data sheet

1. Product profile

1.1 General description

N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology.

1.2 Features

2. Pinning information

Table 1.	Pinning		
Pin	Description	Simplified outline	Symbol
1	gate (G)		_
2	source (S)		
3	drain (D)	2 Transparent top view	G (FA)
		SOT883 (SC-101)	mbb076 Ŝ



3. Ordering information

Table 2. Ordering information					
Type number	Package	Package			
	Name	Description	Version		
PMZ250UN	SC-101	leadless ultra small plastic package; 3 solder lands; body 1.0 \times 0.6 \times 0.5 mm	SOT883		

4. Limiting values

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices. Such precautions are described in the *ANSI/ESD S20.20*, *IEC/ST 61340-5*, *JESD625-A* or

Table 3. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

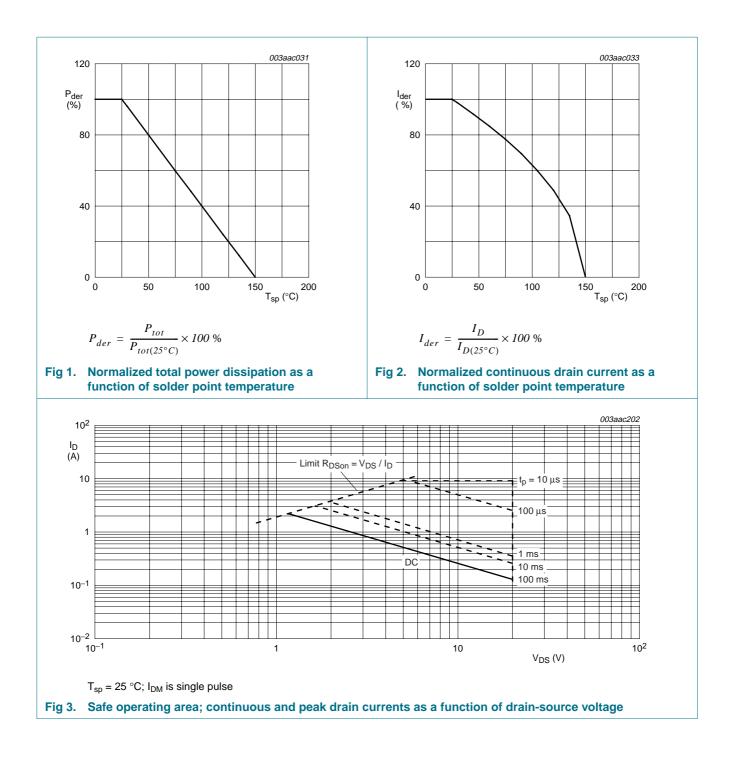
equivalent standards.

Symbol	Parameter	Conditions	Min	Max	Unit
V _{DS}	drain-source voltage	$25 \text{ °C} \leq T_j \leq 150 \text{ °C}$	-	20	V
V _{DGR}	drain-gate voltage (DC)	25 °C \leq T $_{j}$ \leq 150 °C; R $_{GS}$ = 20 k Ω	-	20	V
V _{GS}	gate-source voltage		-	±8	V
I _D	drain current	T_{sp} = 25 °C; V_{GS} = 4.5 V; see <u>Figure 2</u> and <u>3</u>	-	2.28	А
		T_{sp} = 100 °C; V_{GS} = 4.5 V; see <u>Figure 2</u>	-	1.44	А
I _{DM}	peak drain current	T_{sp} = 25 °C; pulsed; $t_p \le 10 \ \mu s$; see Figure 3	-	4.56	А
P _{tot}	total power dissipation	T _{sp} = 25 °C; see <u>Figure 1</u>	-	2.50	W
T _{stg}	storage temperature	-	-55	+150	°C
Tj	junction temperature	-	-55	+150	°C
Source-	drain diode				
I _S	source current	T _{sp} = 25 °C	-	2.28	А
I _{SM}	peak source current	T_{sp} = 25 °C; pulsed; $t_p \le$ 10 μs	-	4.56	А
Electros	tatic discharge				
V _{esd}	electrostatic discharge voltage	all pins	-		
		human body model; C = 100pF; R = 1.5 k Ω	-	60	V
		machine model; C = 200 pF	-	30	V

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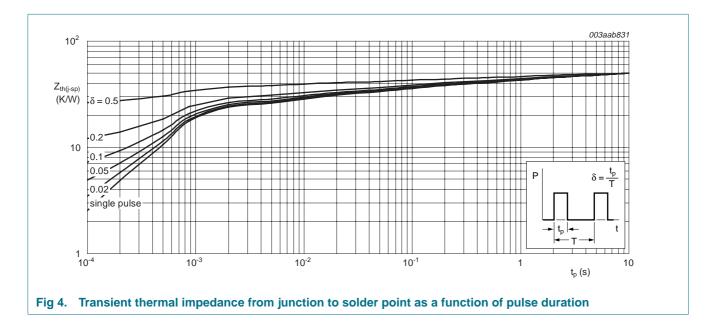
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5. Thermal characteristics

Table 4.Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-sp)}	thermal resistance from junction to solder point	see Figure 4	-	-	50	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	minimum footprint	<u>[1]</u>	670	-	K/W

[1] Mounted on a printed-circuit board; vertical in still air.

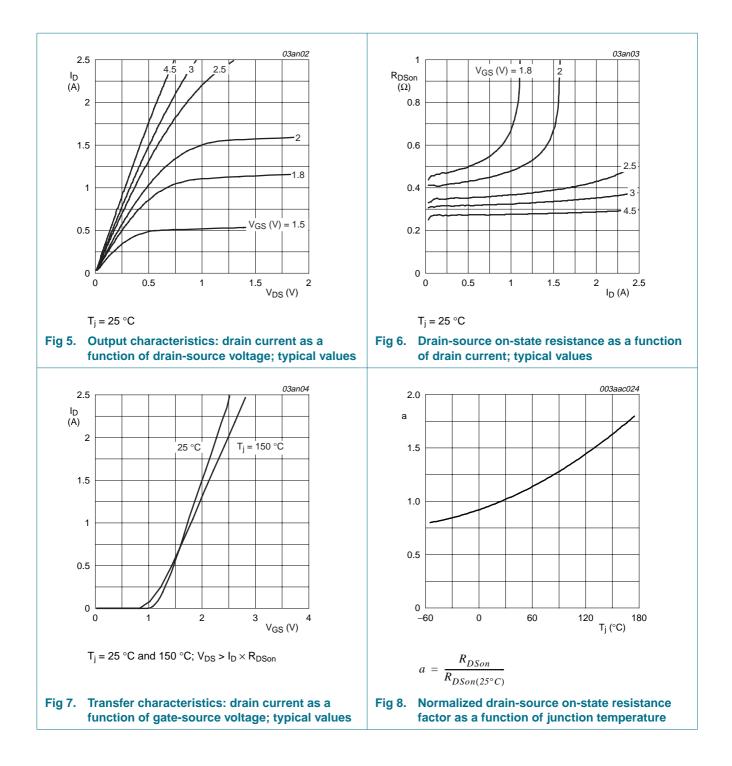


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6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static ch	aracteristics					
V _{(BR)DSS}	drain-source breakdown	$I_D = 10 \ \mu A; \ V_{GS} = 0 \ V$				
	voltage	T _j = 25 °C	20	-	-	V
		T _j = −55 °C	18	-	-	V
V _{GS(th)}	gate-source threshold voltage	$I_D = 0.25$ mA; $V_{DS} = V_{GS}$; see Figure 9 and 10				
		T _j = 25 °C	0.45	0.7	0.95	V
		T _j = 150 °C	0.25	-	-	V
		$T_j = -55 \ ^{\circ}C$	-	-	1.15	V
I _{DSS}	drain leakage current	$V_{DS} = 20 \text{ V}; V_{GS} = 0 \text{ V}$				
		T _j = 25 °C	-	-	1	μA
		T _j = 150 °C	-	-	100	μA
I _{GSS}	gate leakage current	$V_{GS} = \pm 8 V; V_{DS} = 0 V$	-	10	100	nA
R _{DSon}	drain-source on-state resistance	V_{GS} = 4.5 V; I_D = 0.2 A; see <u>Figure 6</u> and <u>8</u>				
		$T_j = 25 \ ^{\circ}C$	-	250	300	mΩ
		T _j = 150 °C	-	400	480	mΩ
		$V_{GS} = 2.5 \text{ V}; I_D = 0.1 \text{ A}; \text{ see } \frac{\text{Figure 6}}{\text{Figure 6}} \text{ and } \frac{8}{2}$	-	320	400	mΩ
		V_{GS} = 1.8 V; I _D = 0.075 A; see <u>Figure 6</u> and <u>8</u>	-	420	600	mΩ
Dynamio	characteristics					
Q _{G(tot)}	total gate charge	I_D = 1 A; V_{DS} = 10 V; V_{GS} = 4.5 V; see	-	0.89	-	nC
Q _{GS}	gate-source charge	Figure 11 and <u>12</u>	-	0.13	-	nC
Q _{GD}	gate-drain charge		-	0.18	-	nC
C _{iss}	input capacitance	$V_{GS} = 0 V$; $V_{DS} = 20 V$; f = 1 MHz; see	-	45	-	pF
C _{oss}	output capacitance	Figure 14	-	11	-	pF
C _{rss}	reverse transfer capacitance		-	7	-	pF
t _{d(on)}	turn-on delay time	V_{DS} = 10 V; R_L = 10 $\Omega;$ V_{GS} = 4.5 V; R_G = 6 Ω	-	4.5	-	ns
t _r	rise time		-	10	-	ns
t _{d(off)}	turn-off delay time		-	18.5	-	ns
t _f	fall time		-	5	-	ns
Source-o	drain diode					
V _{SD}	source-drain voltage	I _S = 0.3 A; V _{GS} = 0 V; see Figure 13	_	0.80	1.2	V

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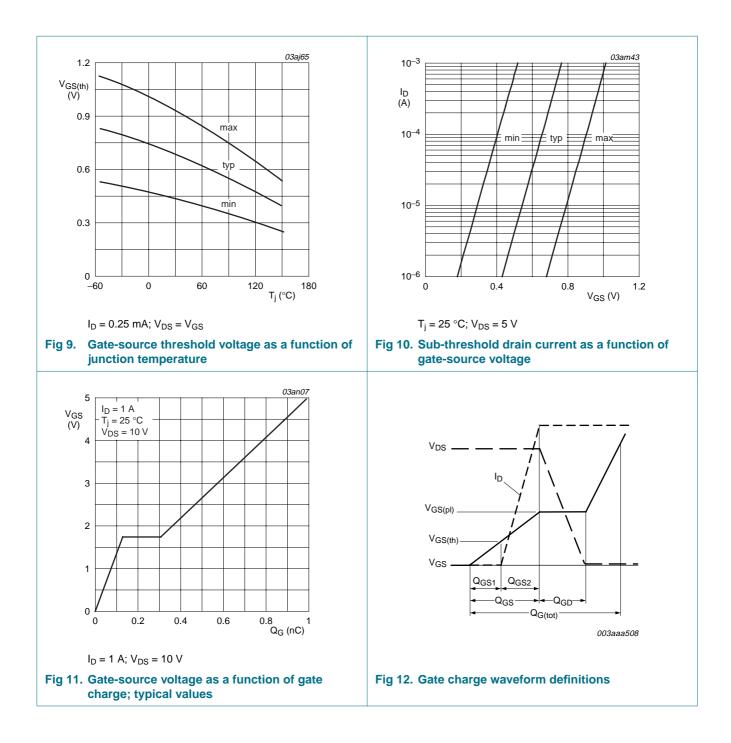


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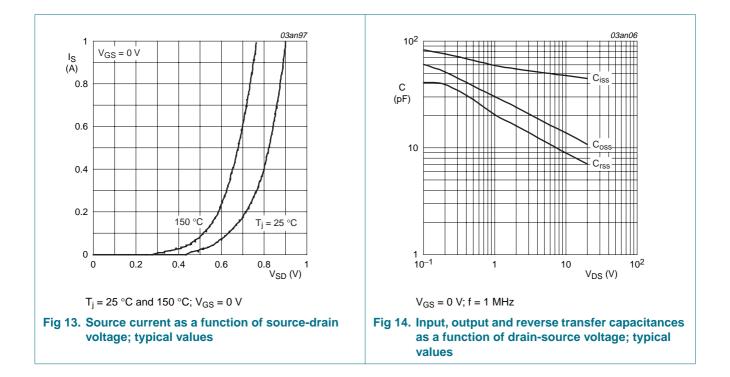
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7. Package outline

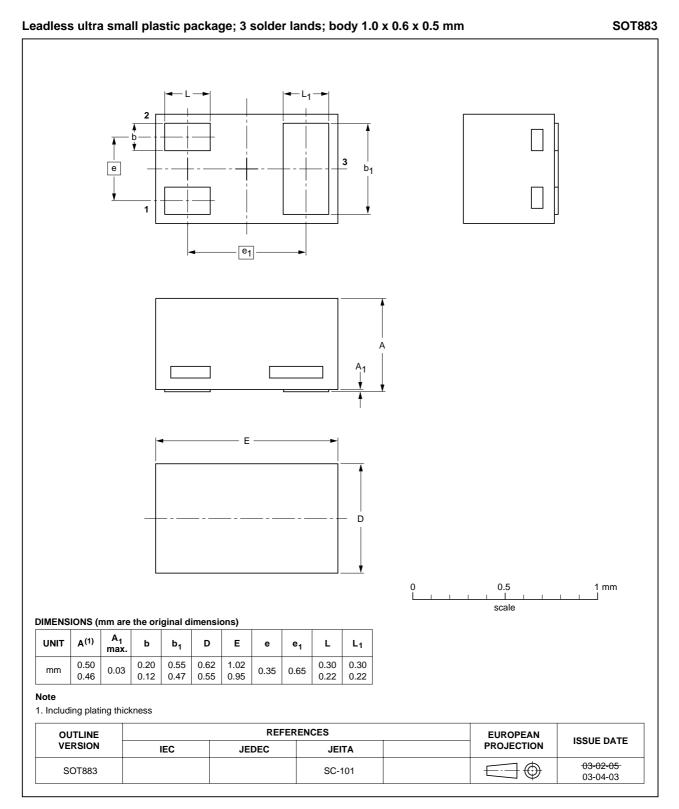
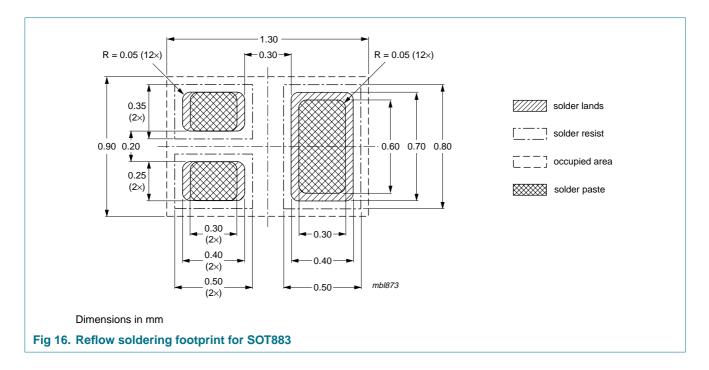


Fig 15. Package outline SOT833 (SC-101)

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8. Soldering



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9. Revision history

Table 6.	e 6. Revision history				
Document	ID	Release date	Data sheet status	Change notice	Supersedes
PMZ250UN	_1	20080221	Product data sheet	-	-

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10. Legal information

10.1 Data sheet status

Document status[1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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Date of release: 21 February 2008 Document identifier: PMZ250UN_1